

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1812	(438/455).OCLS.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/12/04 20:33
L2	1352	(438/458).OCLS.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/12/04 20:33
L3	2355	(257/e21.546).OCLS.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/12/04 20:33
L4	400	(257/e21.561).OCLS.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/12/04 20:34
L5	170	endo-akihiko.in.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:34
L6	115	morimoto-nobuyuki.in.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:35
L7	32	oxidation stack\$3 fault	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:35

L8	32	L7	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:35
L9	111	oxidation with stack \$3 fault and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:35
L10	111	L9	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:35
L11	244	5 or 6	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:36
L12	7	11 and 9	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:36
L13	109	soi and stacking faults and implant\$3 with hydrogen and bond\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:48
L14	109	L13	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:48
L15	0	soi and stacking faults and implant\$3 with hydrogen and bond\$3 and nitrogen concentration	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:50

L16	0	soi and stacking faults and implant\$3 with hydrogen and bond\$3 and nitrogen with concentrarion	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:50
L17	0	soi and stacking faults and implant\$3 with hydrogen and bond\$3 and oxygen with concentrarion	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:50
L18	66	soi and stacking faults and implant\$3 with hydrogen and bond\$3 and nitrogen	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:51
L19	7	soi and stacking faults and implant\$3 with hydrogen and bond\$3 and nitrogen same support\$3 with wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:51
L20	4	soi and stacking faults and implant\$3 with hydrogen and bond\$3 and nitrogen same oxygen same support\$3 with wafer	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/12/04 20:51
S1	28	oxidation stack\$3 fault	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/30 20:38
S2	3	oxidation stack\$3 fault and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/30 20:38

S3	104	oxidation with stack \$3 fault and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/30 20:38
S4	82	oxidation with stack \$3 fault and soi and bond\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/30 20:40
S5	56	oxidation with stack \$3 fault and soi and bond\$3 and implant \$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/30 20:40
S6	30	oxidation with stack \$3 fault and soi and bond\$3 and implant \$3 with (hydrogen or noble gas)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/30 20:42
S7	0	support wafer with osf	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 18:46
S8	0	support wafer same oxidation stacking faults	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 18:47
S9	0	support wafer and oxidation stacking faults	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 18:47
S10	16	support wafer and stacking faults	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 18:48

S11	3	support wafer same stacking faults	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 18:48
S12	471	soi and stacking faults	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 19:33
S13	98	soi and stacking faults and implant\$3 with hydrogen	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 19:34
S14	91	soi and stacking faults and implant\$3 with hydrogen and bond\$3	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 19:34
S15	1	soi and stacking faults same support with wafer and implant\$3 with hydrogen and bond \$3	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 19:35
S16	0	soi and stacking faults same support with wafer and implant\$3 with hydrogen and bond \$3 cleavage	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 19:36
S17	0	soi and stacking faults same support with wafer and implant\$3 with hydrogen and bond \$3 and cleavage	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 19:36
S18	5	soi and stacking faults same wafer and implant\$3 with hydrogen and bond \$3 and cleavage	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 19:37

S19	144	endo-akihiko.in.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 20:14
S20	53	endo-akihiko.in. and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 20:14
S21	6	endo-akihiko.in. and soi and faults	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/03 20:16
S22	141	stack\$3 fault with defect same metal	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 08:46
S23	1	stack\$3 fault with defect with captur \$3 same metal	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 08:47
S24	3	stack\$3 fault with defect same captur \$3 same metal	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 08:47
S25	0	stack\$3 fault and intrinsic getter\$3 and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 08:48
S26	48	stack\$3 fault and intrinsic getter\$3 and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 08:48

S27	3	stack\$3 fault and intrinsic getter\$3 and (support or base) near wafer and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 08:49
S28	19	stack\$3 fault and intrinsic getter\$3 and (handle or support or base) near wafer and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 08:50
S29	19	intrinsic getter\$3 same (handle or support or base) near wafer and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 08:56
S30	90	stack\$3 fault with cop	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 09:20
S31	22	stack\$3 fault with cop and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 09:21
S32	0	intrinsic getter\$3 same (handle or support or base) near wafer and soi and osf	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 09:27
S33	12	intrinsic getter\$3 same (handle or support or base) near wafer and soi and stack\$3 with fault	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 09:27
S34	28	getter\$3 same (handle or support or base) near wafer and soi and stack\$3 with fault	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 09:28

S35	5	stack\$3 with fault same getter\$3 same (handle or support or base) near wafer and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/02/04 09:29
S36	2	("6008110").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/02/04 10:22
S37	2	("5753353").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/02/04 10:23
S38	1641	(438/455).COLS.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/02/04 10:27
S39	1180	(438/458).COLS.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/02/04 10:28
S40	101	old astm	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/06 17:41
S41	33	old astm and osf	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/06 17:46
S42	16	"6224668"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/06 19:03

S43	7	old astm and osf and soi	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/07 18:44
S44	7	endo-akihiko.in. and soi and faults	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/07 18:50
S45	46	oxygen concentration and soi and osf	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/07 18:52
S46	18	oxygen concentration and soi and osf and astm	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/07 18:52
S47	0	wo03092065	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/07 21:15
S48	5	"03092065"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/07 21:15
S49	0	old astm near "1983"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/07 22:17
S50	8	astm near "1983"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/07 22:17

S51	0	old atsm near "1983"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/07 22:18
S52	101	old astm	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/07 22:18
S53	1744	(438/455).COLS.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/12 19:36
S54	1284	(438/458).COLS.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/12 19:36
S55	2254	(257/e21.546).COLS.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/08/12 19:36
S56	163	endo-akihiko.in.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/08/12 19:36

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